

EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|--------|---------------------------------------------|-------------------------------------------------------------------|------------------|---------|------------------|
| L1 | 183521 | source and drain and gate and semiconductor | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/08/28 09:33 |
| L2 | 17061 | l1 and (recess or groove) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/08/28 09:34 |
| L3 | 41271 | gate same (recess or groove) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/08/28 09:34 |
| L4 | 8850 | l1 and l3 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/08/28 09:35 |
| L5 | 1564 | l4 and (width adj5 gate) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/08/28 10:00 |
| L6 | 248 | l4 and (width adj5 gate).clm. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/08/28 10:00 |